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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,092,224	7/2000	LeBlanc et al.			
	5,949,797	9/1999	Jung			
	5,838,692	11/1998	Tobin			
	5,799,021	8/1998	Gheewala			
	5,578,938	11/1996	Kazami			
	5,235,566	8/1993	Merrill			
	5,231,314	7/1993	Andrews			
	5,208,178	5/1993	Usami			
	5,369,643	11/1994	Rastgar et al.			
	6,038,691	3/2000	Nakao et al.			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		Nakao et al., LOW OVERHEAD TEST POINT INSERTION FOR SCAN-BASED BIST, ITC International Test Conference, pages 348-357.
		M. Youssef et al., Methodology for Efficiently Inserting and Condensing Test Points, IEEE Proceedings, Pages 154-160, May 1993.

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.